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| [**S.No**](http://S.No) | **Name** | **Designation/Company** | **Title of Talk** |
| 1 | Govind | Oracle | Reliability |
| 2 | Mayank Srivastava | IISc | An overview of Design and Reliability of Gallium Nitrite HEMT Power Devices |
| 3 | Sivakumar V | Keysight | Holistic approach to DFT: Component to System |
| 4 | Larry | Advantest | IoT-Creating a Cost Effective High MultiSite RF Solution |
| 5 | Larry | Advantest | Evolutionary Value Added, Accelerate New Product Time-to-Market |
| 6 | Shridhar | Intel | High Performance CPU Design and associated HVM/Test Challenges |
| 7 | Jeanne Trinko Mechler | GLOBALFOUNDRIES | DFT design challenges for next generation 7nm FinFET applications |
| 8 | Prashant/Ashish | TI | Functional Safety |
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|  |  |  |  |
| 9 | Krishna C | Cadence |  |
| 10 | Shridhar | Intel | Processor DFT |